

ABSTRACT

Electronics manufacturers, particularly ones building large scale computer systems, have a need to describe test vectors for third party manufacturers in a low level language description that does not reveal the circuit design to the third party but allows for the third party to build and test the systems, not just with static tests based on BSDL and netlist files, but dynamic tests as well. A conversion process for taking a high level language circuitry description and producing test vectors useable for translation into actual test vectors for testing board-level components of the large scale computer systems is described.